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United States Patent [19]

Elie

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[45] **Date of Patent: ** Jun. 16, 1992**

[54] **CONTOUR PLOTTER FOR EYEWEAR**

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[73] Assignee: **Essilor International (Compagnie Generale d'Optique)**, Creteil, France

[**] Term: **14 Years**

[21] Appl. No.: **479,586**

[22] Filed: **Feb. 13, 1990**

[30] **Foreign Application Priority Data**

Aug. 14, 1989 [FR] France 89 5245

[52] **U.S. Cl.** **D10/64**; D10/46

[58] **Field of Search** D10/46, 64, 75; D24/172; 156/242; 33/28, 200, 503, 513; 264/1.1, 1.8; 351/159, 164, 168, 172, 204

[56] **References Cited**

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Scan apparatus by Innovative Research Inc.
Hoya UNILAB Lens Finishing System.
"The Dawn of a New Age", Frame Tracer, by Optical Systems.

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[57] **CLAIM**

The ornamental design for a contour plotter for eyewear, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a contour plotter for eyewear showing my new design, shown with the cover in an open condition;
FIG. **2** is a perspective view, shown with the cover in a closed condition;
FIG. **3** is a top plan view of FIG. **1** thereof;
FIG. **4** is a bottom plan view;
FIG. **5** is a front elevational view;
FIG. **6** is a rear elevational view;
FIG. **7** is a left side elevational view; and,
FIG. **8** is a right side elevational view thereof.
FIGS. **1** and **2** has been drawn on a slightly enlarged scale with respect to FIGS. **3–8.**

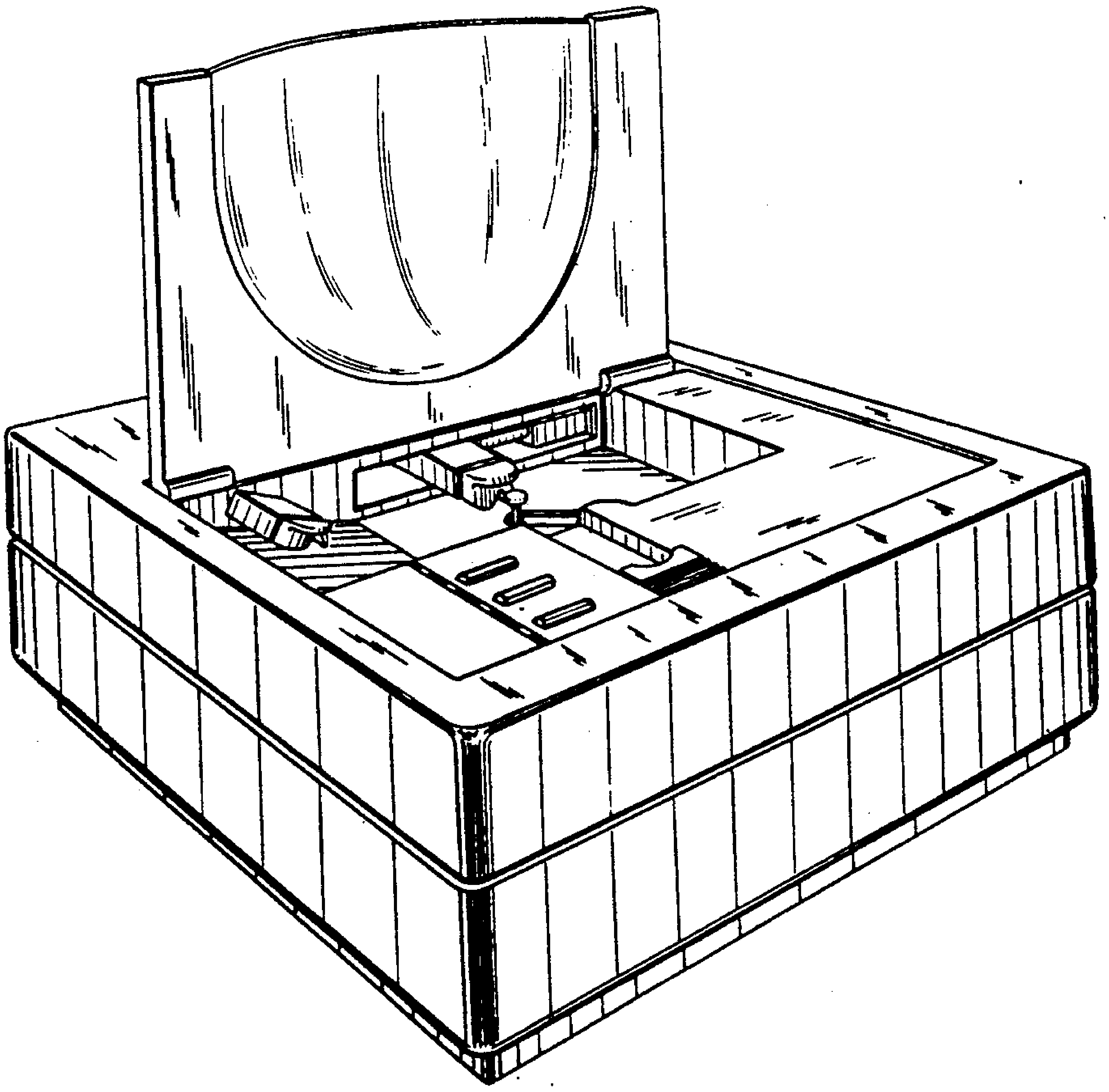

FIG. 1

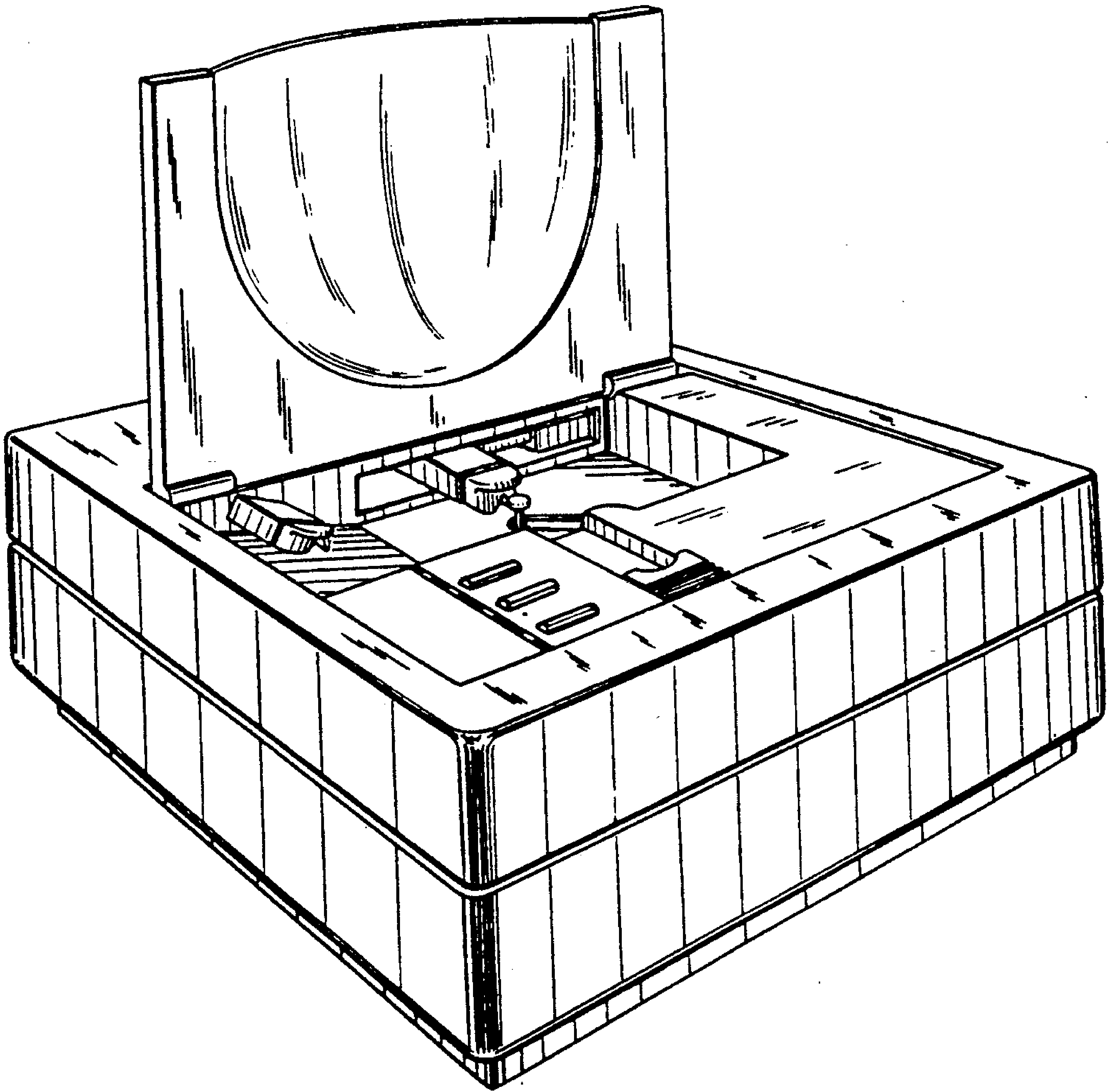

FIG. 2

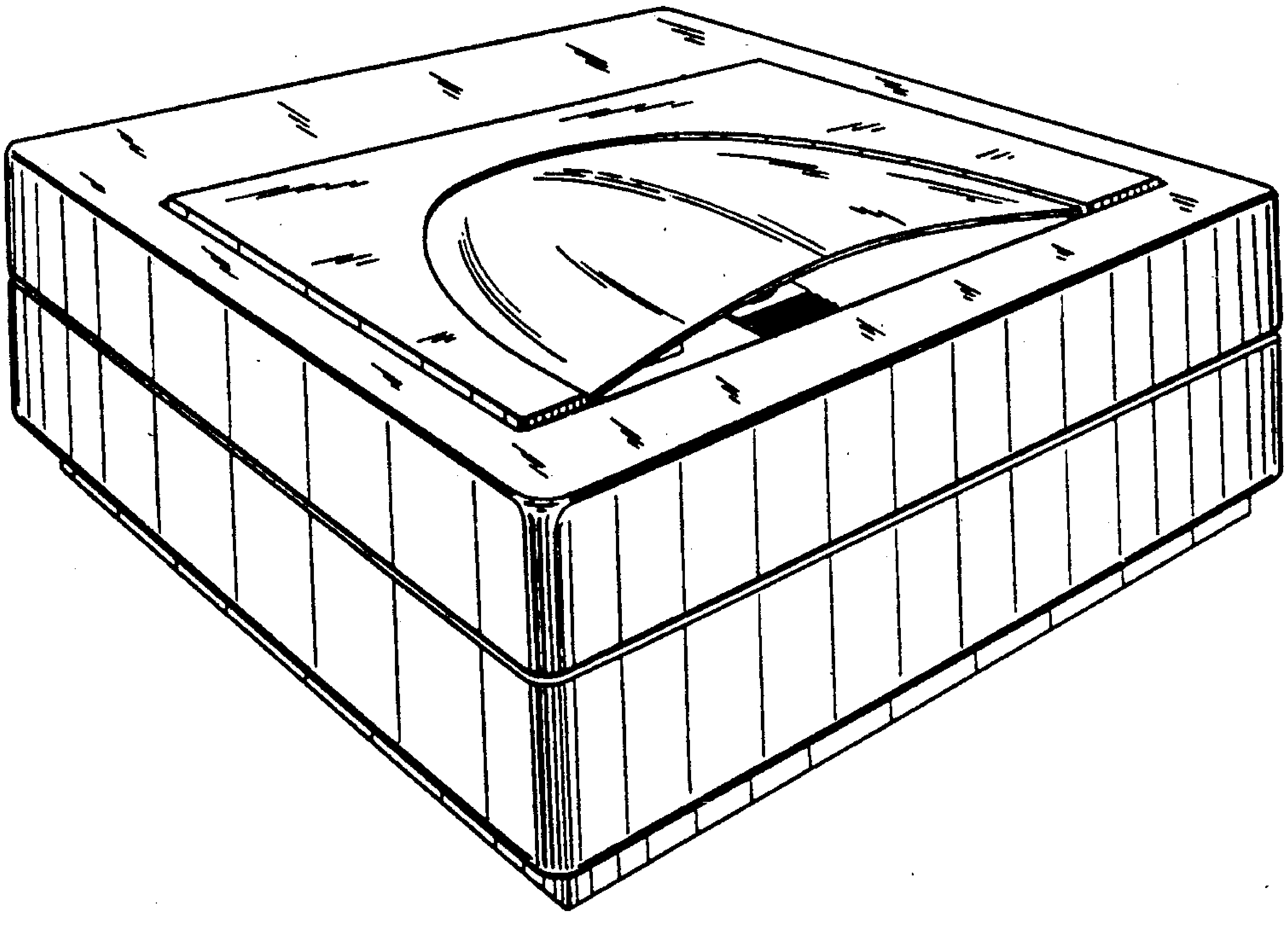

FIG. 3

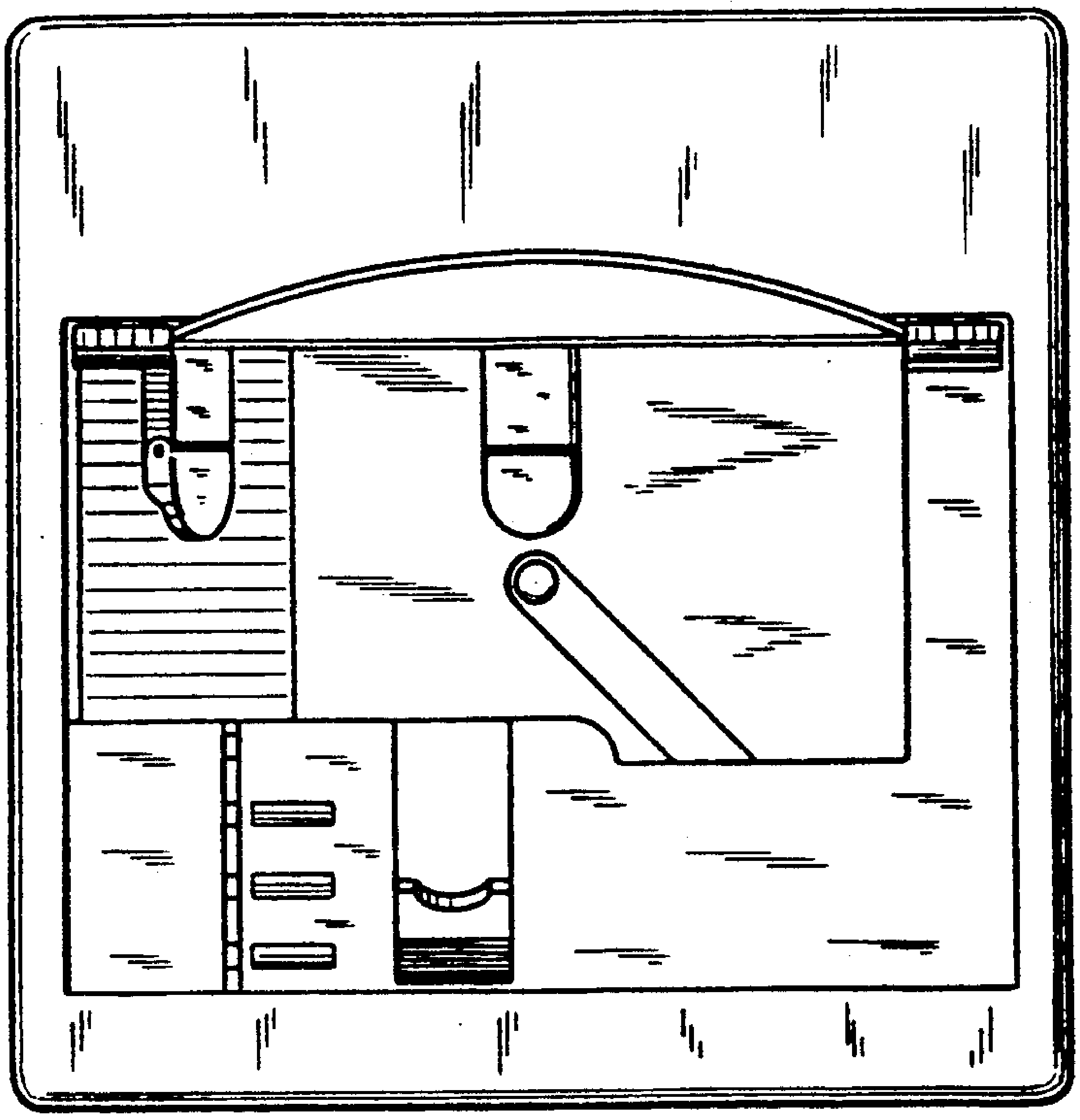

FIG. 4

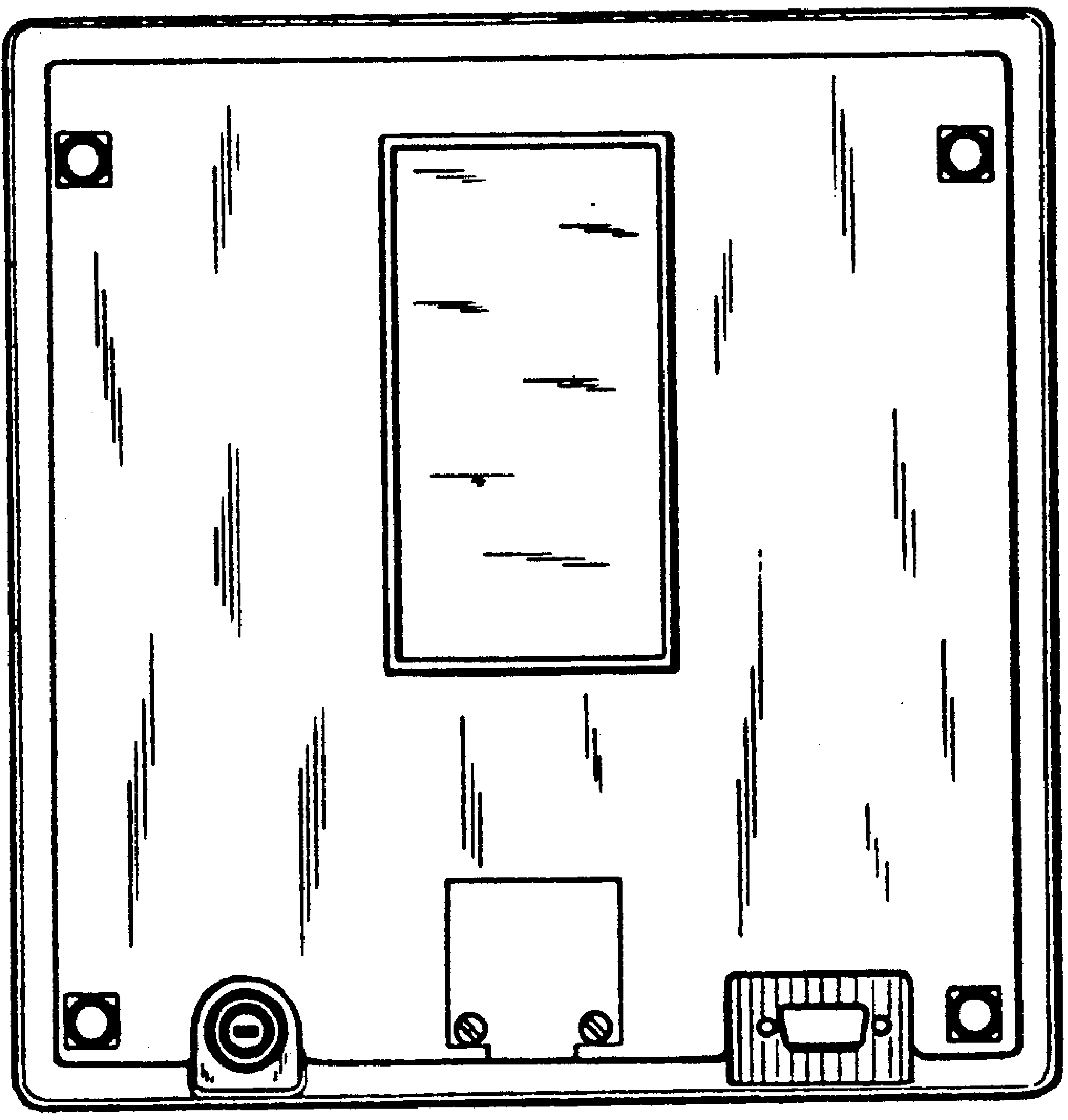

FIG. 5

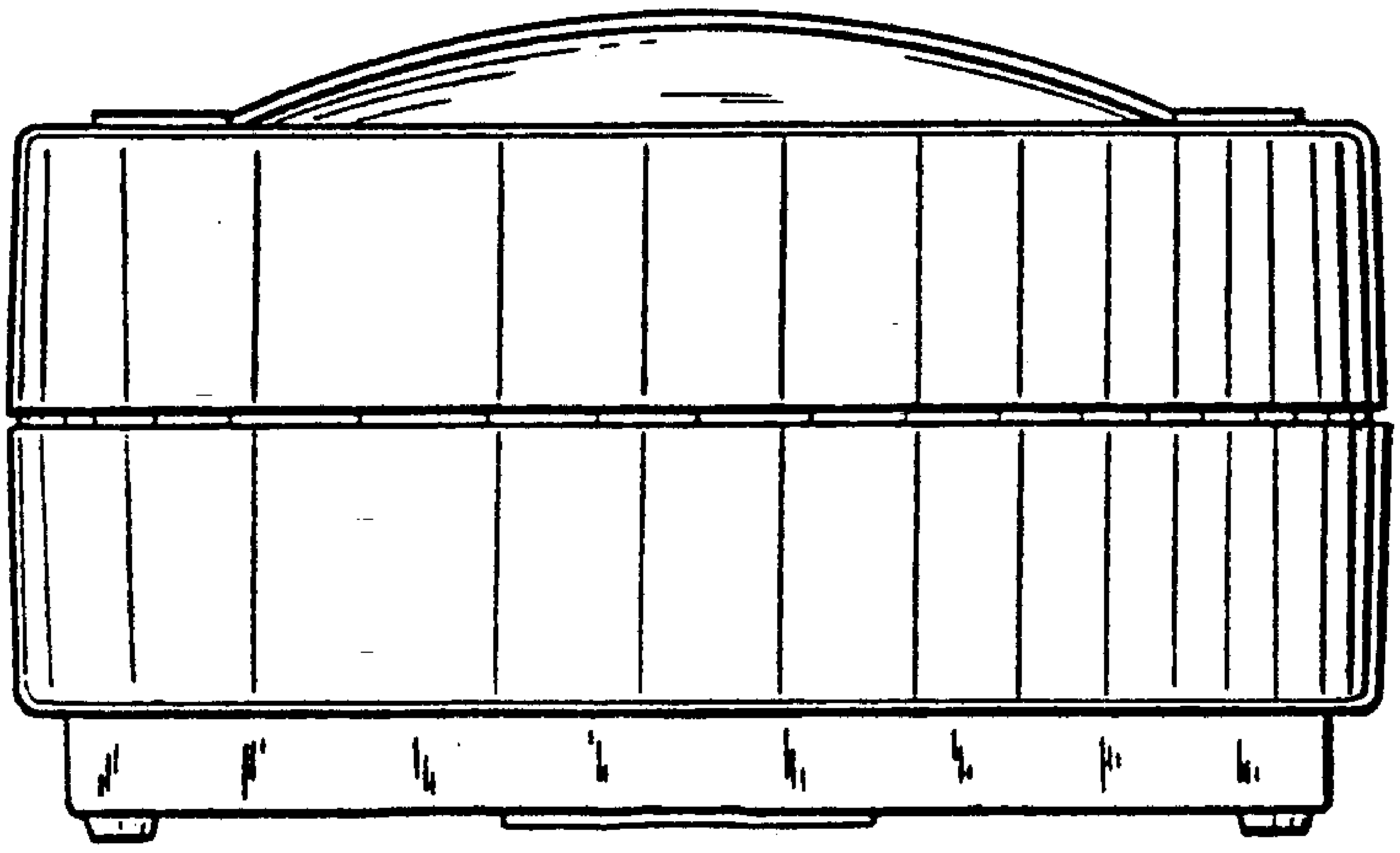

FIG. 6

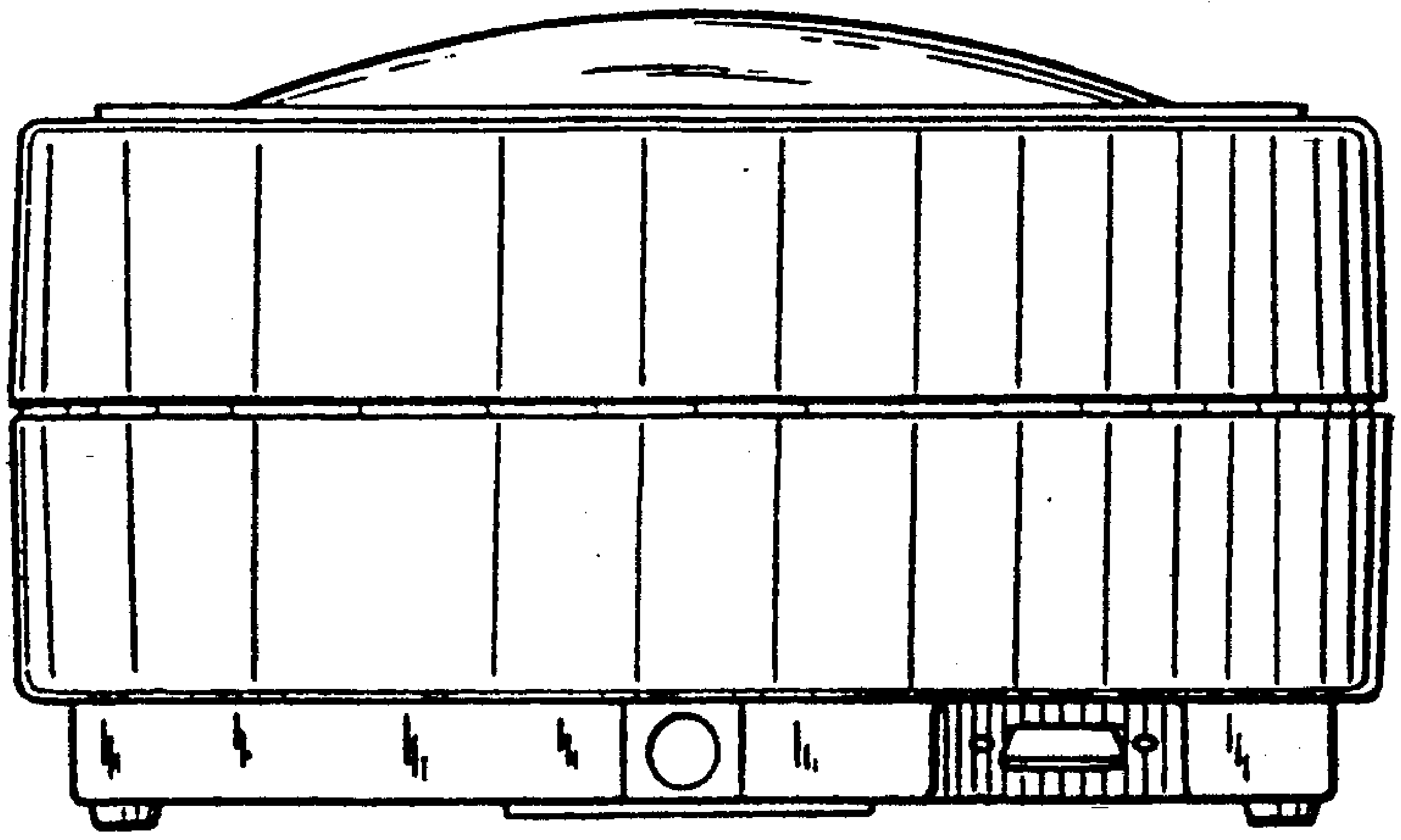

FIG. 7

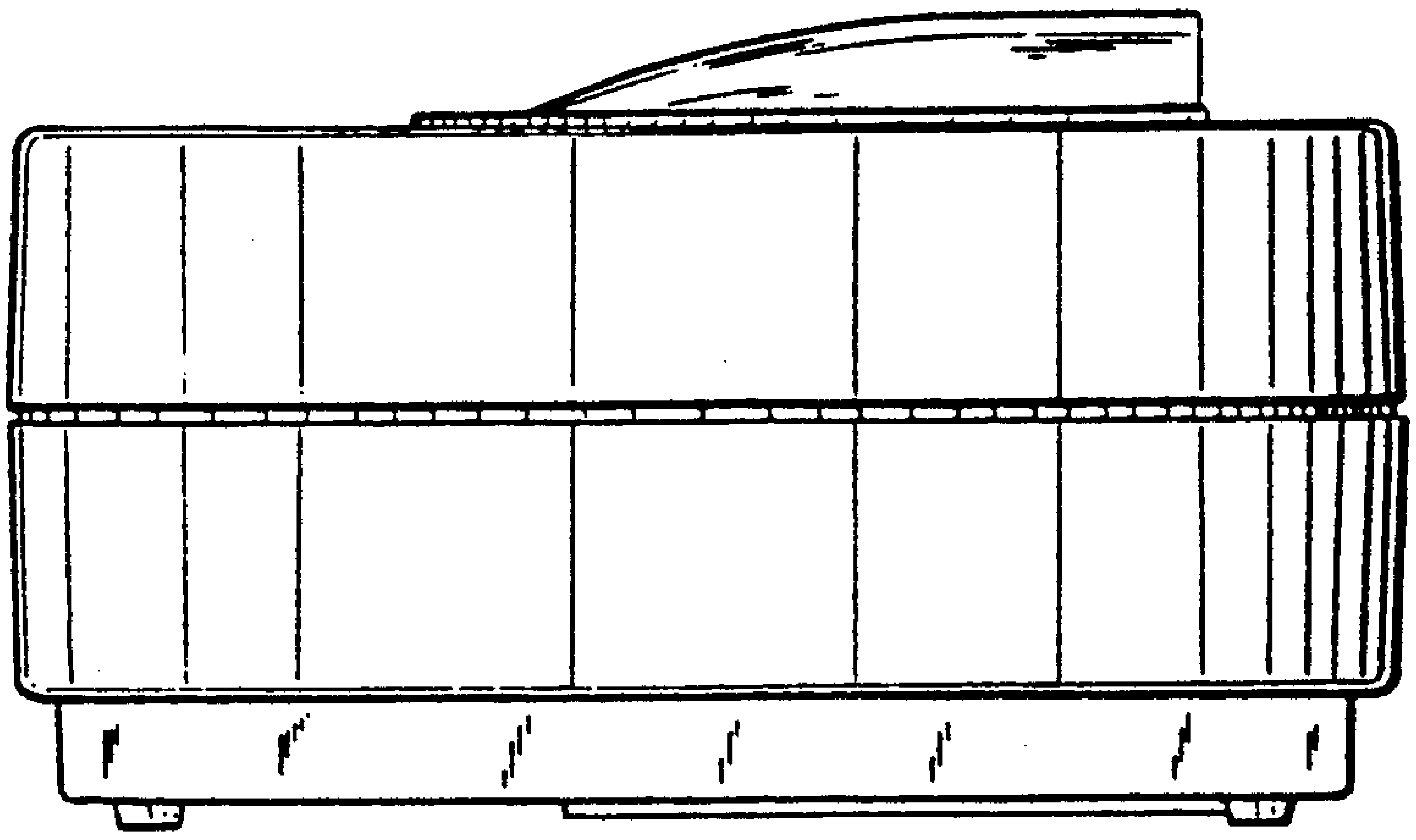

FIG. 8